Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/537,767	ENDO ET AL.
Examiner	Art Unit
lae W. Lee	1656

	SEARCHED				
Class	Subclass	Date	Examiner		
NONE	NONE	12/20/2006	JWL		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
STN databases: BIOSIS, CAPLUS, EMBASE, MEDLINE, SCISEARCH, AND JAPIO, see attached search history printouts	12/20/2006	JWL		
See search results available by SCORE	12/20/2006	JWL		
PALM inventor name search	12/20/2006	JWL		
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